

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/774,924	<b>Applicant(s)/Patent under Reexamination</b> CHANG, HSUEH CHIN
	<b>Examiner</b> David M. Fenstermacher	<b>Art Unit</b> 3682

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner